

<b>Notice of References Cited</b>	Application/Control No. 10/617,821	Applicant(s)/Patent Under Reexamination YOU ET AL.	
	Examiner David G. Cervetti	Art Unit 2136	Page 1 of 3

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,809,326 A	02-1989	Shigenaga, Yoshimi	705/73
*	B	US-5,809,230 A	09-1998	Pereira, J. L. A.	726/35
*	C	US-5,845,260 A	12-1998	Nakano et al.	705/26
*	D	US-5,881,225 A	03-1999	Worth, Erik K.	726/17
*	E	US-5,970,143 A	10-1999	Schneier et al.	713/181
*	F	US-2002/0031230 A1	03-2002	Sweet et al.	380/278
*	G	US-2002/0049806 A1	04-2002	Gatz et al.	709/203
*	H	US-2002/0145632 A1	10-2002	Shmueli et al.	345/835
*	I	US-2002/0147912 A1	10-2002	Shmueli et al.	713/182
*	J	US-2002/0147653 A1	10-2002	Shmueli et al.	705/26
*	K	US-2002/0143637 A1	10-2002	Shmueli et al.	705/26
*	L	US-2002/0162009 A1	10-2002	Shmueli et al.	713/200
*	M	US-6,519,412 B1	02-2003	Kim, Young-Chul	386/94

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	RAT Control, Aug. 2000, <a href="http://web.archive.org/web/20000815061847/www.armadillo.com.hk/maincatalog.html">http://web.archive.org/web/20000815061847/www.armadillo.com.hk/maincatalog.html</a>
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. 10/617,821	Applicant(s)/Patent Under Reexamination YOU ET AL.	
	Examiner David G. Cervetti	Art Unit 2136	Page 2 of 3

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,539,430 B1	03-2003	Humes, Donald Creig	709/225
*	B	US-2003/0132285 A1	07-2003	Blancas et al.	235/380
*	C	US-6,662,365 B1	12-2003	Sullivan et al.	725/25
*	D	US-6,678,824 B1	01-2004	Cannon et al.	726/22
*	E	US-2004/0003079 A1	01-2004	Aiu et al.	709/225
*	F	US-2004/0065731 A1	04-2004	Vesterling, Friedrich	235/382
*	G	US-6,754,641 B2	06-2004	Kolls, H. Brock	705/44
*	H	US-2004/0139018 A1	07-2004	Anderson et al.	705/041
*	I	US-6,785,824 B1	08-2004	Grassle, Geoffrey J.	726/30
*	J	US-6,934,753 B2	08-2005	Kim, Tae-Ju	709/225
*	K	US-6,986,030 B2	01-2006	Shmueli et al.	713/1
*	L	US-7,080,039 B1	07-2006	Marsh, David J	705/51
*	M	US-7,100,053 B1	08-2006	Brown et al.	713/185

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. 10/617,821	Applicant(s)/Patent Under Reexamination YOU ET AL.	
	Examiner David G. Cervetti	Art Unit 2136	Page 3 of 3

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,124,426 B1	10-2006	Tsuria et al.	725/75
*	B	US-7,124,938 B1	10-2006	Marsh, David J	235/382
*	C	US-7,181,626 B1	02-2007	Rasmussen, Brian	713/185
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.